

Abstract Submitted
for the MAR10 Meeting of
The American Physical Society

Electronic properties of coupled interfaces in LaAlO₃/SrTiO₃ heterostructures G.W.J. HASSINK, J.A. BOSCHKER, G. KOSTER, G. RIJNDERS, D.H.A. BLANK, MESA+ Institute for Nanotechnology, University of Twente, the Netherlands — The electron density at the LaAlO₃//SrTiO₃ interface is a function of the separation between the doped interface and a second interface [Nat.Mat. 5, 556-560]. Depending on the nature of the second interface, either *n*-type LaO//TiO₂ or *p*-type AlO₂//SrO, the electron doping decreases resp. increases with increasing interface separation. This observation can be explained by assuming a *p*-type interface acts as an electron sink, while a *n*-type interface acts as an electron source. Here we extend the research to coupled interfaces with two *n*-type interfaces fabricated using pulsed laser deposition. Applying a microscopic dipole model to the polar discontinuity inherent to the system allows for the extraction of the binding energy for both cases. The positive value for *p*-type interfaces shows that electrons from the primary *n*-type interface are indeed trapped, while the negative value for the secondary *n*-type interfaces indicates that electrons are doped away from the donor interface.

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Date submitted: 11 Nov 2009

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